
**Optics and photonics — Lasers and
laser-related equipment — Test
methods for laser beam power
(energy) density distribution**

*Optique et photonique — Lasers et équipements associés aux
lasers — Méthodes d'essai de distribution de la densité de puissance
(d'énergie) du faisceau laser*

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Foreword

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This document was prepared by Technical Committee ISO/TC 172, *Optics and photonics*, Subcommittee SC 9, *Laser and electro-optical systems*.

This third edition cancels and replaces the second edition (ISO 13694:2015), which has been technically revised. The main changes compared to the previous edition are as follows:

- a) the definition of beam ellipticity has been harmonized with ISO 11145 and ISO 11146-1;
- b) the term “second linear moments” has been replaced by “second moments”;
- c) the term “field of view” has been replaced by “aperture”;
- d) [Clause 9](#) was rewritten; the paragraphs on clip-levels were corrected to reflect that they are no longer intended for noise cancelation;
- e) the entries “Fitted distribution type”, “Roughness of fit R”, and “Goodness of fit G” have been removed from the Test Report;
- f) the term “aspect ratio” has been removed from the test report.

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